

Notice of References Cited	Application/Control No. 10/632,467	Applicant(s)/Patent Under Reexamination WATANABE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0010732	01-2005	Boyd et al.	711/162
	B	US-2003/0204583	10-2003	Kaneda et al.	709/223
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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